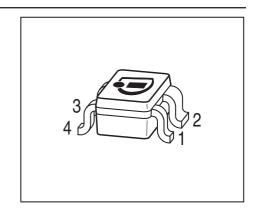


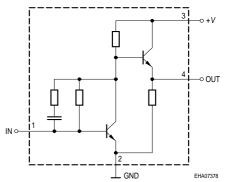
# Si-MMIC-Amplifier in SIEGET® 25-Technologie

- Cascadable 50 Ω-gain block
- Unconditionally stable
- Gain  $|S_{21}|^2$  = 18.5 dB at 1.8 GHz (Appl.1) gain  $|S_{21}|^2$  = 22 dB at 1.8 GHz (Appl.2)  $IP_{3out}$  = +7 dBm at 1.8 GHz ( $V_D$ =3V,  $I_D$ =9.4mA)
- Noise figure NF = 2.2 dB at 1.8 GHz
- Typical device voltage  $V_D$  = 2 V to 5 V
- Reverse isolation > 35 dB (Appl.2)
- Pb-free (RoHS compliant) package



**Circuit Diagram** 





### ESD (Electrostatic discharge) sensitive device, observe handling precaution!

Туре	Marking	Pin Configuration			Package	
BGA427	BMs	1, IN	2, GND	3, +V	4, Out	SOT343

### **Maximum Ratings**

Parameter	Symbol	Value	Unit
Device current	I <sub>D</sub>	25	mA
Device voltage	V <sub>D</sub> ,+V	6	V
Total power dissipation	P <sub>tot</sub>	150	mW
<i>T</i> <sub>S</sub> = 120 °C			
RF input power	P <sub>RFin</sub>	-10	dBm
Junction temperature	T <sub>j</sub>	150	°C
Ambient temperature range	T <sub>A</sub>	-65 150	
Storage temperature range	$T_{ m stq}$	-65 150	

#### **Thermal Resistance**

Junction - soldering point <sup>1)</sup>	R <sub>thJS</sub>	≤ 295	K/W

 $<sup>^{1}\</sup>mathrm{For}$  calculation of  $R_{\mathrm{thJA}}$  please refer to Application Note Thermal Resistance

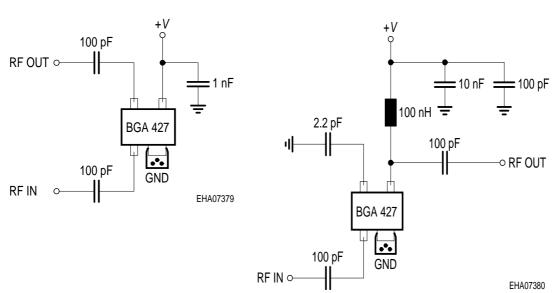


**Electrical Characteristics** at  $T_{\rm A}$  = 25 °C, unless otherwise specified.

Parameter	Symbol		Values		
		min.	typ.	max.	
<b>AC</b> characteristics $V_D = 3 \text{ V}$ , $Z_0 = 50\Omega$ ,	•	•	•		
Insertion power gain	$ S_{21} ^2$				dB
f = 0.1 GHz		-	27	_	
f = 1 GHz		-	22	_	
f = 1.8 GHz		-	18.5	-	
Reverse isolation	S12	-	22	-	
f = 1.8 GHz					
Noise figure	NF				
f = 0.1 GHz		-	1.9	_	
f = 1 GHz		-	2	_	
f = 1.8 GHz		-	2.2	-	
Intercept point at the output	IP <sub>3out</sub>	-	+ 7	-	dBm
f = 1.8 GHz					
Return loss input	RLin	-	>12	-	dB
f = 1.8 GHz					
Return loss output	RLout	-	>9	-	
f = 1.8 GHz					

### **Typical configuration**

# Appl.1 Appl.2



Note: 1) Large-value capacitors should be connected from pin 3 to ground right at the device to provide a low impedance path (appl.1).

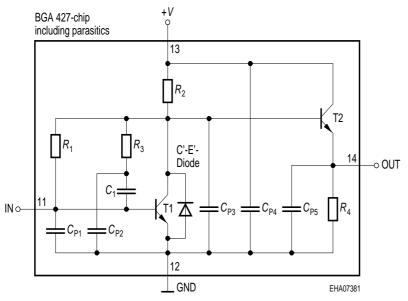
2) The use of plated through holes right at pin 2 is essential for pc-board-applications. Thin boards are recommended to minimize the parasitic inductance to ground.



S-Parameters at  $T_A$  = 25 °C, (Testfixture, Appl.1)

f	S <sub>11</sub>		3	S <sub>21</sub>		S <sub>12</sub>		S <sub>22</sub>
GHz	MAG	ANG	MAG	ANG	MAG	ANG	MAG	ANG
$V_{\rm D}$ = 3V, $Z_{\rm o}$ = 50 $\Omega$								
0.1	0.1382	-38.3	24.821	164.9	0.0022	50.7	0.6435	174.8
0.2	0.1179	-16	24.606	158.9	0.0046	71.8	0.6278	166.9
0.5	0.1697	-20.8	22.236	135.2	0.0104	83.8	0.54	147.3
8.0	0.1824	-56.9	18.258	115.4	0.0169	94.8	0.4453	140.2
0.9	0.1782	-69.1	17.152	109.4	0.0194	97.3	0.4326	139.4
1	0.176	-80.6	15.786	104	0.0225	98.3	0.4129	138.1
1.5	0.1827	-133.5	10.923	84.9	0.0385	99.7	0.3852	139.6
1.8	0.1969	-156.1	9.029	77	0.0479	99.3	0.3917	139.3
1.9	0.2021	-162.8	8.486	74.7	0.0517	98.9	0.3946	138.8
2	0.2116	-167.7	8.015	72.3	0.0549	98.8	0.3991	138.3
2.5	0.2437	172.8	6.259	63	0.0709	97.1	0.4202	134.6
3	0.258	153.3	5.103	55	0.0892	96.9	0.4477	131

# Spice-model BGA 427



T=0.4
T501
T501
14.5k $Ω$
280Ω
$2.4k\Omega$
170Ω
2.3pF
0.2pF
0.2pF
0.6pF
0.1pF
0.1pF
T1



### Transistor Chip Data T1 (Berkley-SPICE 2G.6 Syntax):

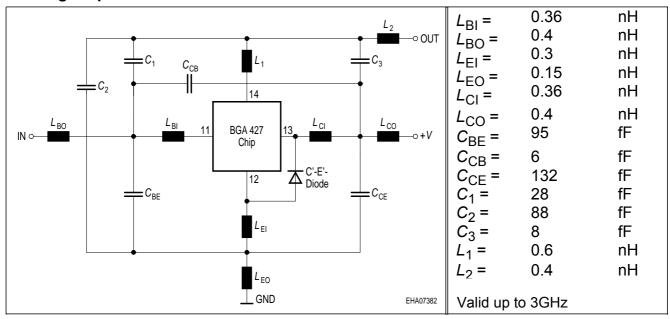
IS =	0.21024	fA	BF =	83.23	_	NF =	1.0405	-
VAF =	39.251	V	IKF =	0.16493	Α	ISE =	15.761	fA
NE =	1.7763	-	BR =	10.526	-	NR =	0.96647	-
VAR =	34.368	V	IKR =	0.25052	Α	ISC =	0.037223	fA
NC =	1.3152	-	RB =	15	Ω	IRB =	0.21215	Α
RBM =	1.3491	Ω	RE =	1.9289		RC =	0.12691	Ω
CJE =	3.7265	fF	VJE =	0.70367	V	MJE =	0.37747	-
TF =	4.5899	ps	XTF =	0.3641	-	VTF =	0.19762	V
ITF =	1.3364	mA	PTF =	0	deg	CJC =	96.941	fF
VJC =	0.99532	V	MJC =	0.48652	-	XCJC =	0.08161	-
TR =	1.4935	ns	CJS =	0	fF	VJS =	0.75	V
MJS =	0	-	XTB =	0	-	EG =	1.11	eV
XTI =	3	-	FC =	0.99469	_	TNOM	300	K

### C'-E'-Diode Data (Berkley-SPICE 2G.6 Syntax) :

IS =	2	fA	N =	1 02	_	RS =	20	Ω
10	_	17 1	I W -	1.02				

All parameters are ready to use, no scaling is necessary

### Package Equivalent Circuit:



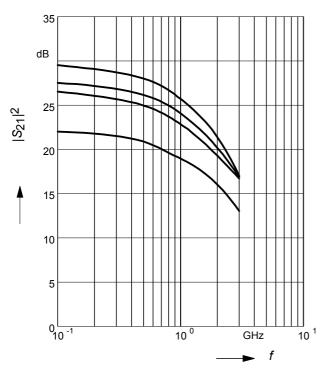
Extracted on behalf of Infineon Technologies AG by: Institut für Mobil-und Satellitentechnik (IMST)

For examples and ready to use parameters please contact your local Infineon Technologies distributor or sales office to obtain a Infineon Technologies CD-ROM or see Internet: http://www.infineon.com/silicondiscretes



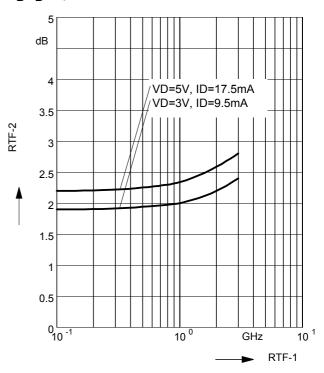
# Insertion power gain $|S_{21}|^2 = f(f)$

## $V_{\rm D}$ , $I_{\rm D}$ = parameter



# Noise figure NF = f(f)

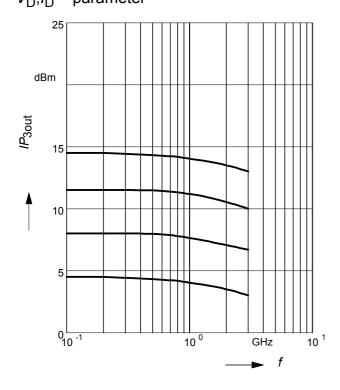
$$V_{\rm D}$$
, $I_{\rm D}$  = parameter



## Intercept point at the output

$$IP_{3out} = f(f)$$

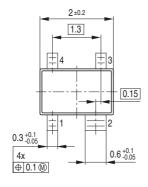
$$V_{\rm D}$$
, $I_{\rm D}$  = parameter

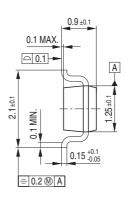




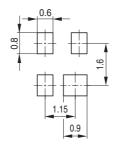
## Package Outline



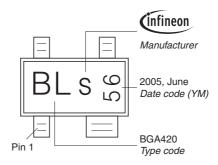




### Foot Print

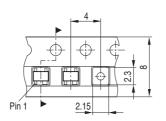


## Marking Layout (Example)



## Standard Packing

Reel ø180 mm = 3.000 Pieces/Reel Reel ø330 mm = 10.000 Pieces/Reel







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